

CERTIFICATE OF MAILING UNDER 37 C.F.R. §1.6

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail, with sufficient postage, in an envelope addressed to: Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450, on the below date:

Date: January 21, 2005 Name: John G. Rauch

Signature: 

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JAN 25 2005

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Initial Appln. of: Frankowsky, Gerd

Appln. No.: 10/624,031

Filed: July 21, 2003

For: MEMORY DEVICE AND
METHOD OF STORING FAIL
ADDRESSES OF A MEMORY
CELL

Attorney Docket No: 10808/101

Examiner: Nguyen, Dang T.

Art Unit: 2824

INFORMATION DISCLOSURE STATEMENT

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and §§1.97-1.98, and more particularly in accordance with 37 C.F.R. §1.97(d), Applicant hereby cites the following reference(s):

DOCUMENT NUMBER Number-Kind Code (if known)	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
US 2003/0005353 A1	1/2/2003	Mullins, et al.	714/5	5/31/2002
US 6,539,506 B1	3/25/2003	Lammers, et al.	714/719	11/1/1999

DOCUMENT NUMBER Number-Kind Code (if known)	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES OR NO
EP 1 008 993 A2	6/14/2000	EP	G11C 29/00	No

Tarr, M. et al., "Defect Analysis System Speeds Test and Repair of Redundant Memories," Electronics, VNU Business Publications, vol. 57, no. 1, January 12, 1984, pages 175-179.
International Search Report for counterpart international patent application number PCT/EP2004/07740, dated 11/9/2004, 7 pages.

Applicant is enclosing Form PTO-1449 (one sheet), along with a copy of each listed reference for which a copy is required under 37 C.F.R. §1.98(a)(2). EPO

publication number EP 1 008 993 A2 is in the German language. The enclosed PCT search report identifies U.S. Patent number US 6,539,506 B1 as an equivalent family member. Therefore, U.S. Patent number US 6,539,506 B1 is submitted in lieu of a translation of publication number EP 1 008 993 A2.

Applicant respectfully requests the Examiner's consideration of the above reference(s) and entry thereof into the record of this application.

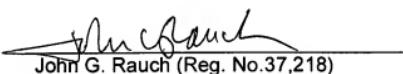
By submitting this Statement, Applicant is attempting to fully comply with the duty of candor and good faith mandated by 37 C.F.R. §1.56. As such, this Statement is not intended to constitute an admission that any of the enclosed references, or other information referred to therein, constitutes "prior art" or is otherwise "material to patentability," as that phrase is defined in 37 C.F.R. §1.56(a).

Applicant hereby certifies pursuant to 37 C.F.R. §1.97(e)(1) that no item of information in this Statement was first cited in any communication from a foreign patent office in a counterpart foreign application more than three months prior to the filing of this Statement (a copy of any foreign communication first citing a listed reference is attached for the Examiner's reference). Therefore, applicant has calculated no fee to be due upon filing this Statement. However, the Director is authorized to charge any fee deficiency associated with the filing of this Statement to Deposit Account No. 23-1925, as authorized in the accompanying Transmittal.

Respectfully submitted,

January 21, 2005

Date



John G. Rauch (Reg. No. 37,218)



FORM PTO-1449	SERIAL NO.	CASE NO.
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (use several sheets if necessary)	10/624,031	10808/101 GROUP ART UNIT 2824 APPLICANT(S): Frankowsky, Gerd

REFERENCE DESIGNATION **U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
A1	US 2003/0055353 A1	1/2/2003	Mullins, et al.	714/5	5/31/2002
A2	US 6,539,506 B1	3/25/2003	Lammers, et al.	714/719	11/1/1999

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES OR NO
A3	EP 1 008 993 A2	6/14/2000	EP	G11C 29/00	No

EXAMINER INITIAL **OTHER ART – NON PATENT LITERATURE DOCUMENTS**

(Include name of author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.

A4	Tarr, M. et al., "Defect Analysis System Speeds Test and Repair of Redundant Memories," Electronics, VNU Business Publications, vol. 57, no. 1, January 12, 1984, pages 175-179.
A5	International Search Report for counterpart international patent application number PCT/EP2004/07740, dated 11/9/2004, 7 pages.

EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.